

Diffusion Studies in Mg-Al-Zn

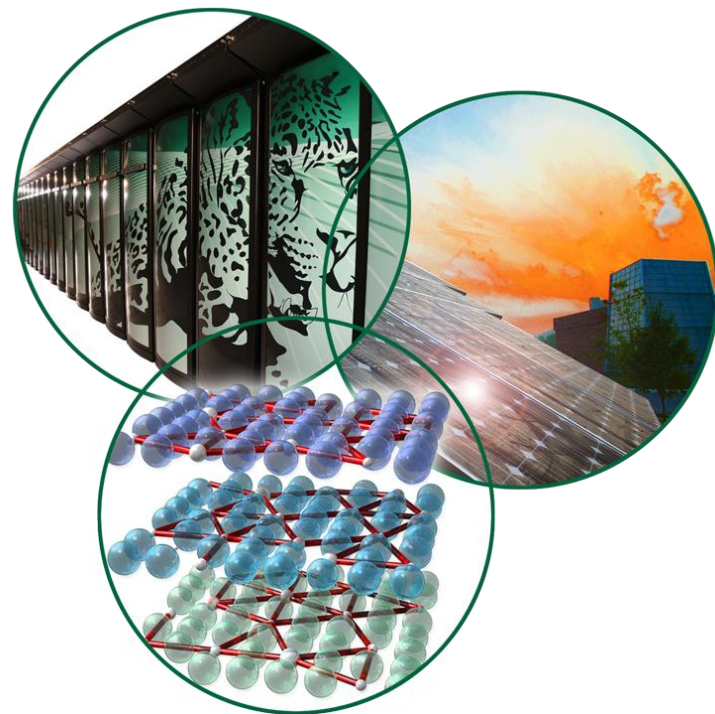


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Phil Sklad, Dave Warren: Automotive Lightweight Materials Program, ORNL

Collaborations and Coordination



- Annealing
- Analysis
- Modeling



Theory

$$\delta C = C_0 \frac{\delta \xi}{2\sqrt{\pi Dt}} \exp\left(-\frac{\xi^2}{4Dt}\right)$$

ORNL
project
Coordination



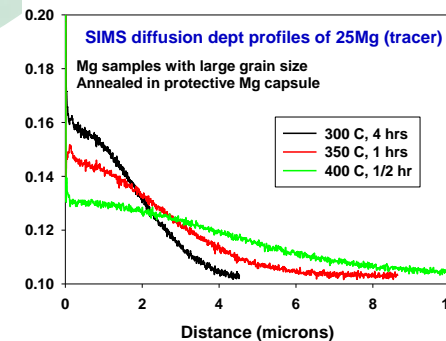
- Coating
- Interdiffusion
- Analysis



- SIMS
- XPS
- Characterization



- Material casting
- Extrusion



Objective

- To develop a Mg tracer diffusion database for Mg, Zn, Al in magnesium-rich alloys for incorporation in the Integrated Computational Engineering (ICME) project

Approach/Strategy

- Measure tracer diffusion coefficients of Mg and Zn in the Mg-Al-Zn-Mn system using secondary ion mass spectrometry (SIMS)
- Tracer diffusion data are preferred for database incorporation: robust, accurate, assumption-free, easier to utilize
- In case of a monoisotopic element such as Al, interdiffusion data will be combined with measured tracer diffusivities along with thermodynamics to extract tracer coefficients using diffusion theory (e.g., Darken/Manning theories)

Onsager Diffusion Formalism

- Intrinsic fluxes where driving forces are chemical potential gradients (Onsager):

$$J_k = - \sum_i L_{ki}^n \text{grad}(\mu_i) \quad \sum_k J_k = -J_v$$

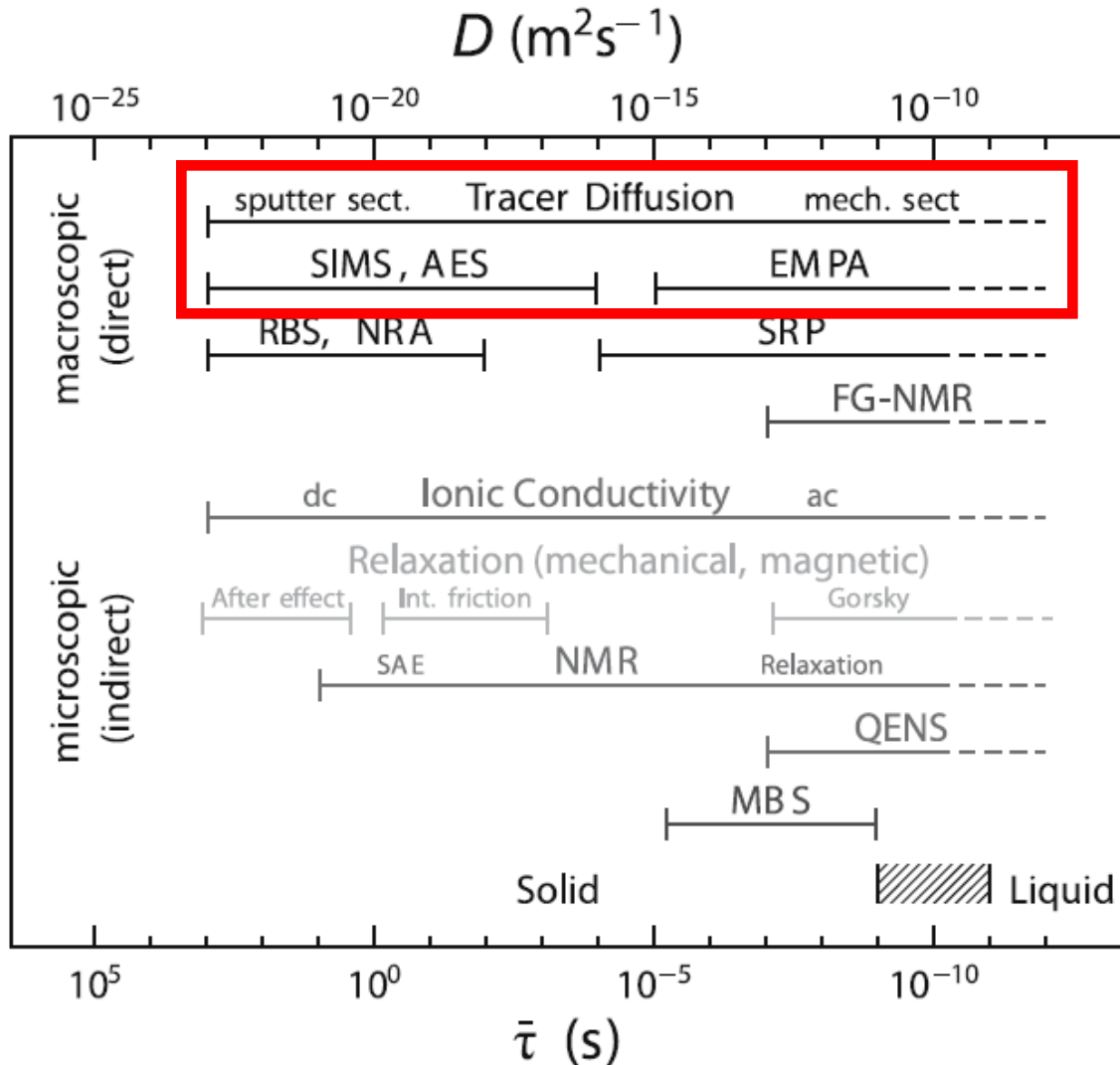
- L_{ki} 's obtained from tracer diffusion data using Manning relations:

$$L_{ii} = \frac{C_i D_i^*}{kT} \left(1 + \frac{2C_i D_i^*}{M_0 \sum_k C_k D_k^*} \right) \quad L_{ij} = \frac{2C_i D_i^* 2C_j D_j^*}{kT M_0 \sum_k C_k D_k^*} \quad i \neq j$$

- Chemical potentials from thermodynamic database
 - *Cross-terms are not ignored as in Darken (correlation effects influence cross-terms)*
 - *Tracer diffusion data is independent of thermodynamic database*

Tracer Diffusion

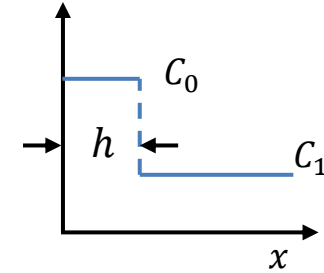
Data over large temperature range



Typical ranges of diffusivity (Mehrer, "Diffusion in Solids")

1D Theory

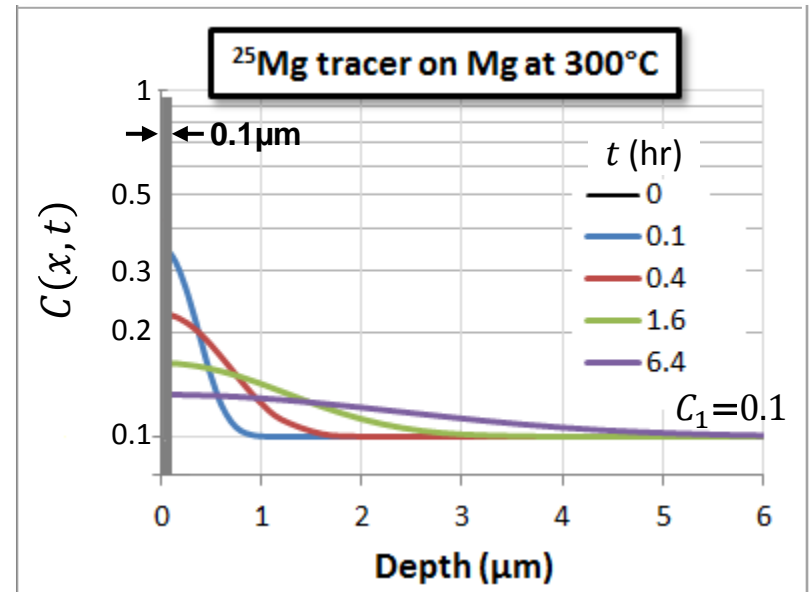
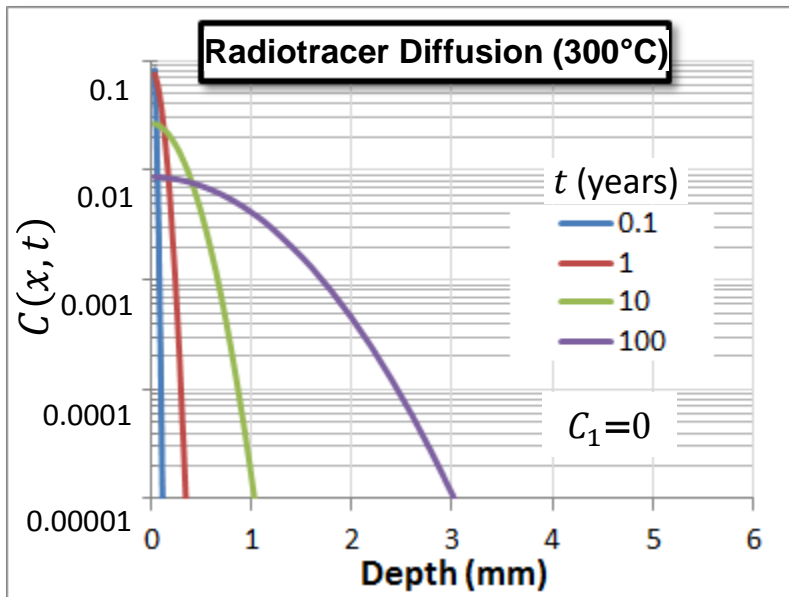
Slab diffusing into material (constant D)



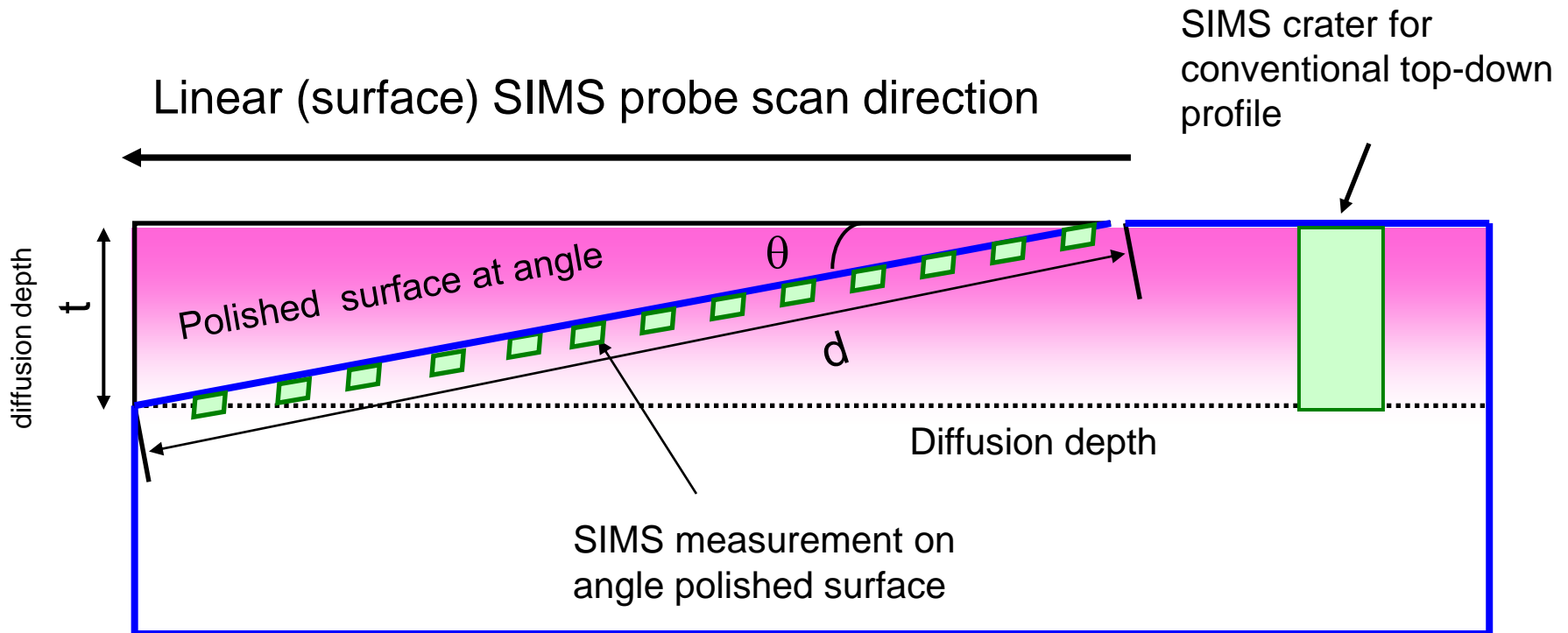
$$C(x, t) - C_1 = \frac{(C_0 - C_1)}{2} \left[\operatorname{erf} \left(\frac{x + h}{2\sqrt{Dt}} \right) - \operatorname{erf} \left(\frac{x - h}{2\sqrt{Dt}} \right) \right]$$

$$C(x, t) - C_1 \approx (C_0 - C_1) \frac{h}{\sqrt{\pi Dt}} \exp \left(-\frac{x^2}{4Dt} \right) \quad h \ll 2\sqrt{Dt}$$

Mg Abundances			
Isotope	^{24}Mg	^{25}Mg	^{26}Mg
Natural	0.7899	0.1001	0.1100
Tracer	0.0180	0.9787	0.0033



Angle polish SIMS for shallow or deep diffusion depths



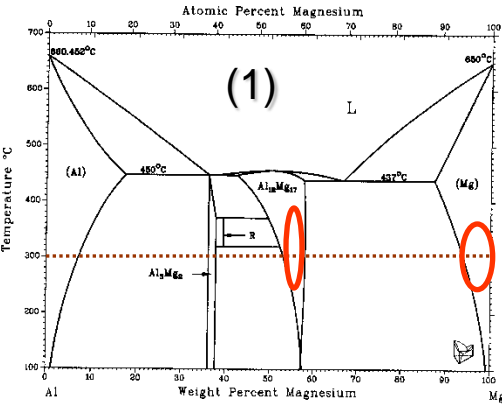
$d = t / \sin(\theta)$: angle polish surface used for SIMS discrete/depth profile measurements

$t = 100 \mu\text{m}$: tracer diffusion depth

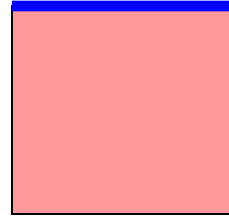
$\theta = 1 \text{ deg}$; $d = 5730 \mu\text{m}$; **Magnification = $5730 / 100 \sim 57$**

Hence, $5730/20 \sim 286$ discrete SIMS measurements every $20 \mu\text{m}$ along d

Tracer Diffusion: SIMS-based thin-film stable-isotope technique

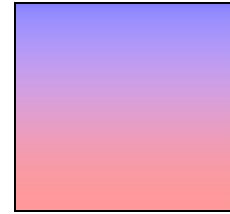


(2)

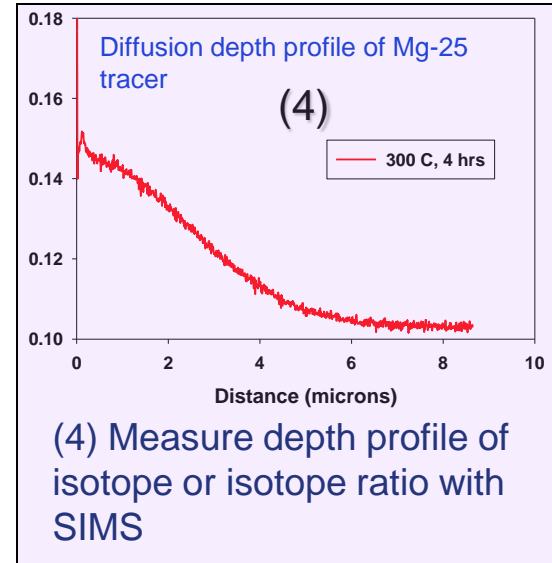


(2) Deposit thin film (100 nm) of stable isotope of an alloy element (e.g., Mg²⁶) on annealed sample

(3)



(3) Anneal at T₀ for desired times (mins to hrs) to cause isotope to diffuse inwards

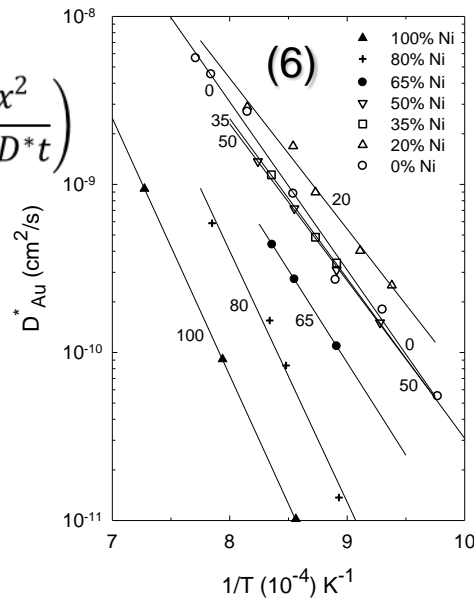


(4) Measure depth profile of isotope or isotope ratio with SIMS

(5)

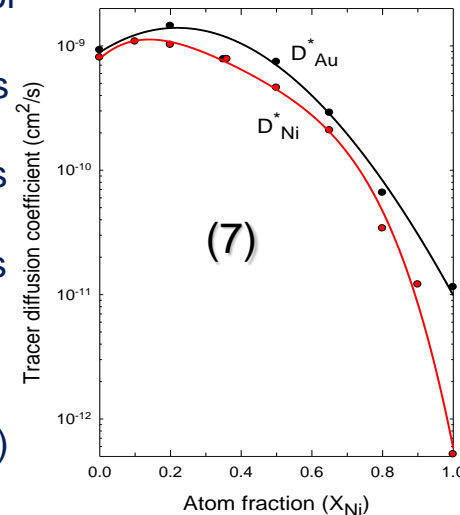
$$C^*(x, t) \approx \frac{h}{\sqrt{\pi D^* t}} \exp\left(-\frac{x^2}{4D^* t}\right)$$

(5) Fit depth profile data for isotope in (4) with above thin-film solution to extract tracer diffusivity D^* .



(6) Repeat for different temperatures and compositions to check for Arrhenius fits (e.g. Au in Au-Ni alloys, Kurtz et al., Acta Met. '55)

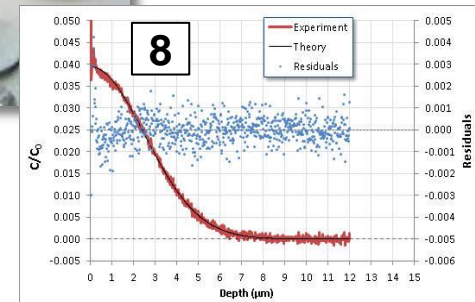
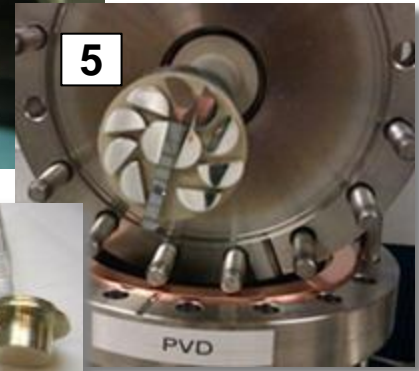
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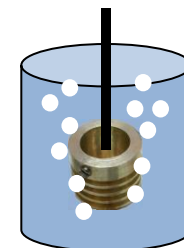
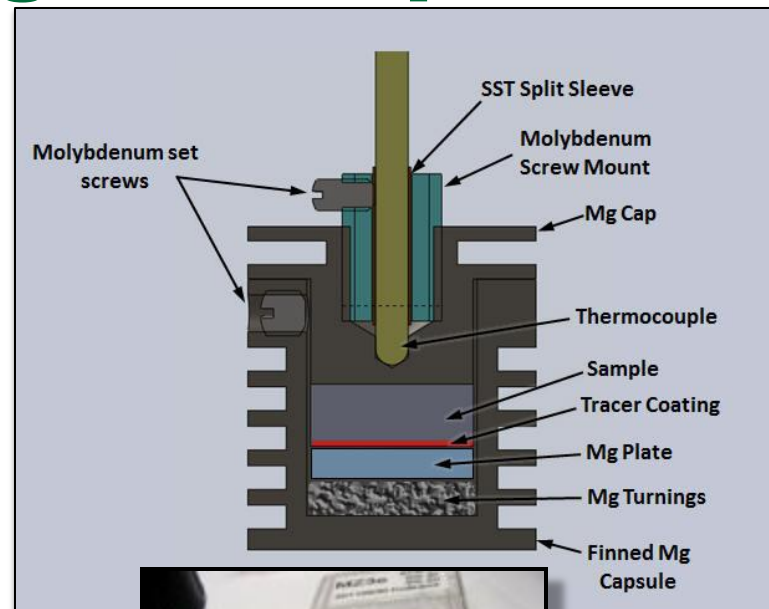
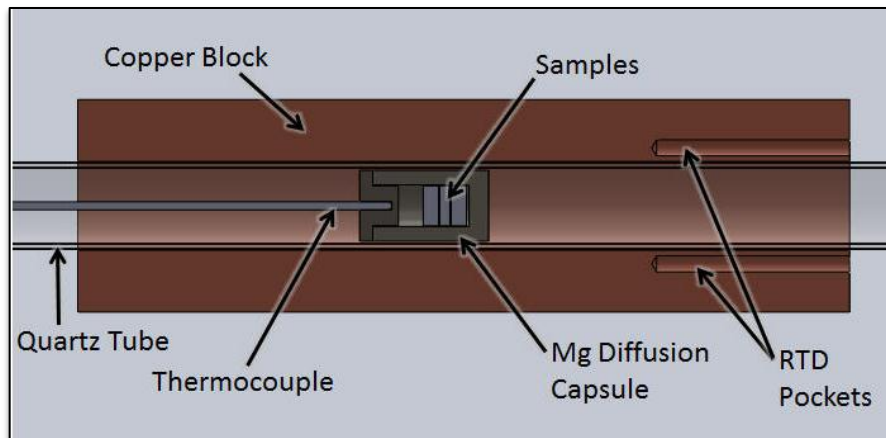
(7) Fit using suitable polynomials for functional form of isotopic diffusivity $D_k^*(X_1, X_2, \dots, T)$ (e.g. Au-Ni tracer diffusion at 900°C, Reynolds et al. Acta Met. '57)

Process Sequence

1. Single phase alloy extrusion
2. Homogenization and grain-growth anneal
3. Sectioning
4. Conditioning anneal
5. Polishing/Coating
6. Annealing
7. SIMS profiling
8. Analysis



Diffusion annealing technique



- Design allows rapid heating (Cu block, fin design) and cooling (liquid nitrogen)
- Mg capsule & turnings act as natural getter to prevent oxidation
- Thermocouple in capsule allows full correction and more accurate analysis especially for short anneal times (10 minutes)

Secondary Ion Mass Spectrometry

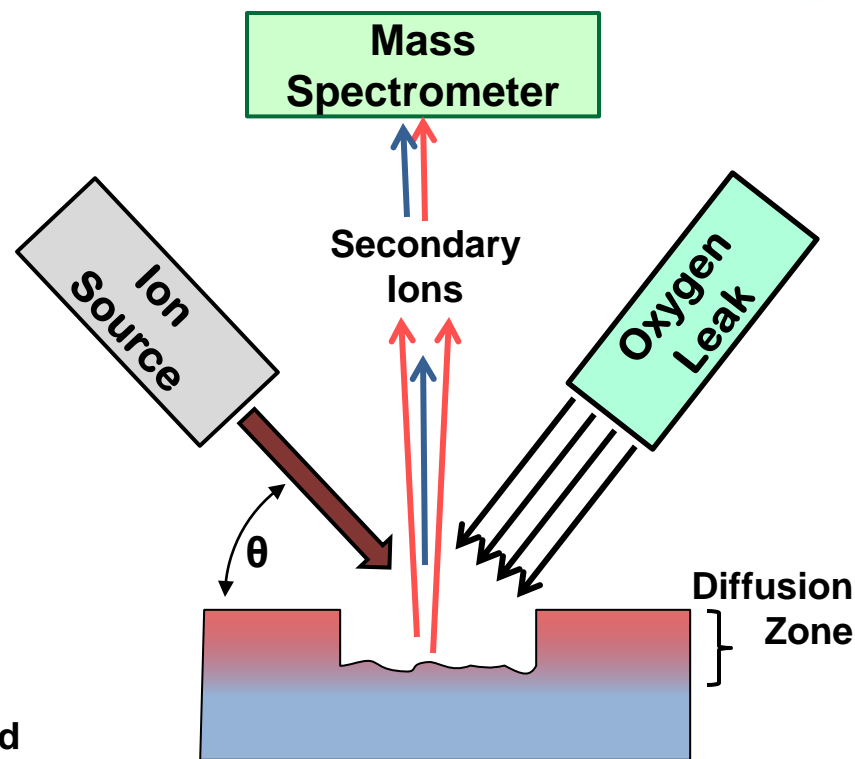


- Roughness increases with sputter depth for polycrystalline samples due to grain orientation
- Oxygen leak creates an amorphous oxide surface to reduce grain orientation effects
- Also, energy and angle are optimized to reduce roughness

Energy, kV	O-leak	Angle	Roughness, nm
Unspattered			7.2
3	yes	37	10.7
2	yes	40.6	10.7
3	yes	40.6	12.2
3	yes	46	17.4
3	no	46	30.7
5	no	44	37.7

} Optimized

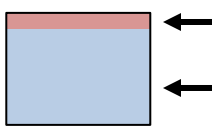
← Typical



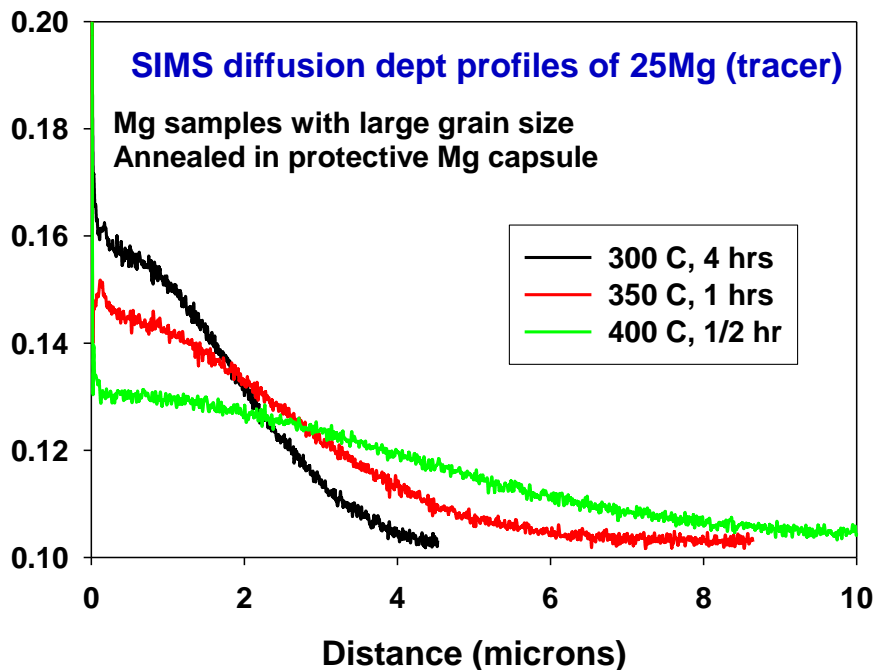
National Laboratory

Experimental Mg self-diffusion

Initial

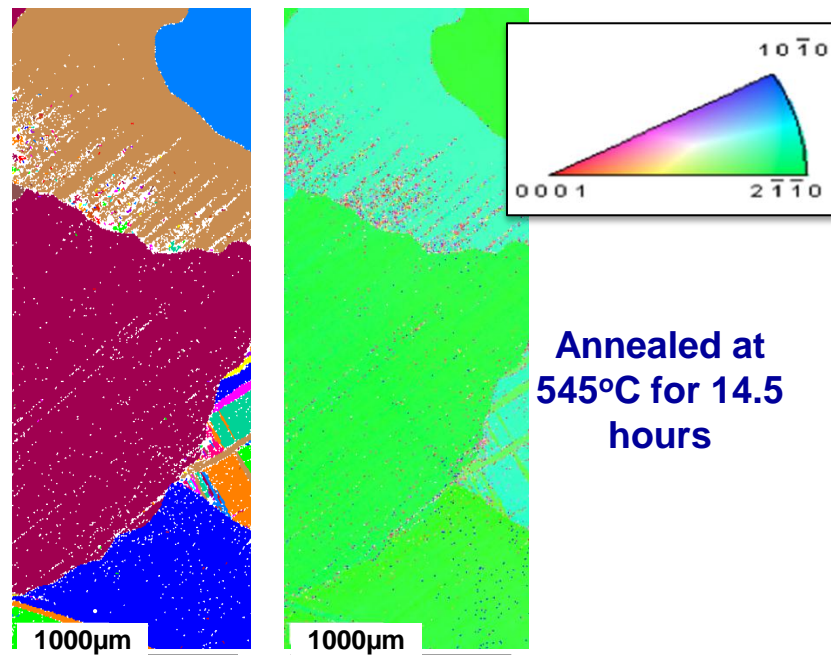


	²⁴ Mg	²⁵ Mg	²⁶ Mg
Tracer	0.018	0.979	0.003
Bulk	0.790	0.100	0.110



SIMS concentration depth profiles of ²⁵Mg

Annealing produces large grains

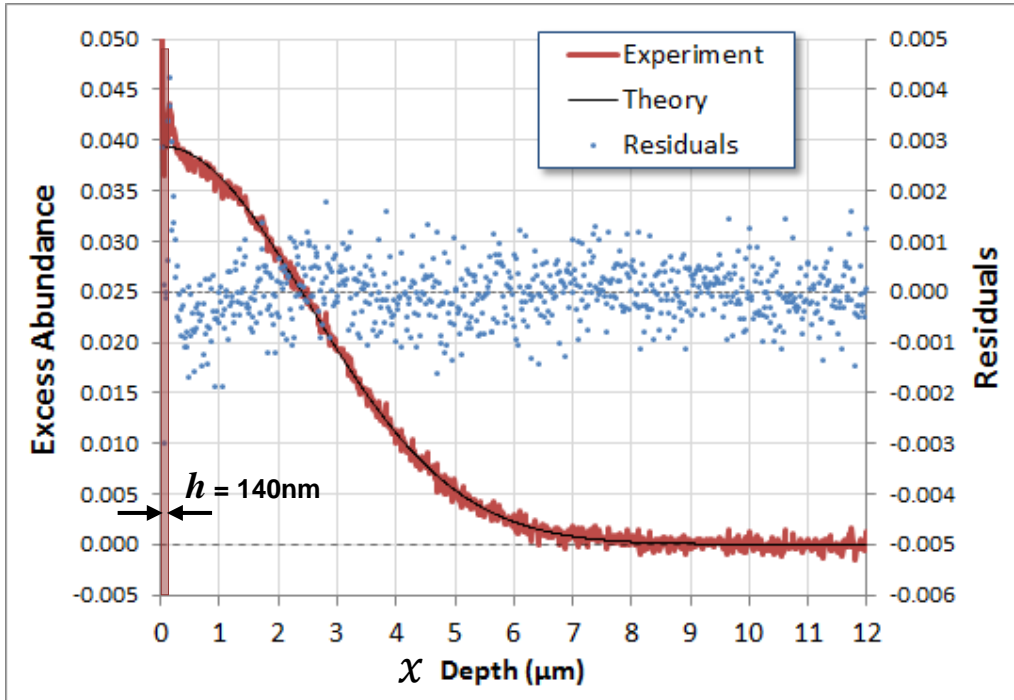


Electron Backscatter Diffraction (EBSD) map (inverse pole figure – top right) of grain orientations in a pure polycrystalline Mg rod after annealing treatment. *left*. Identical grain structure map with enhanced contrast.

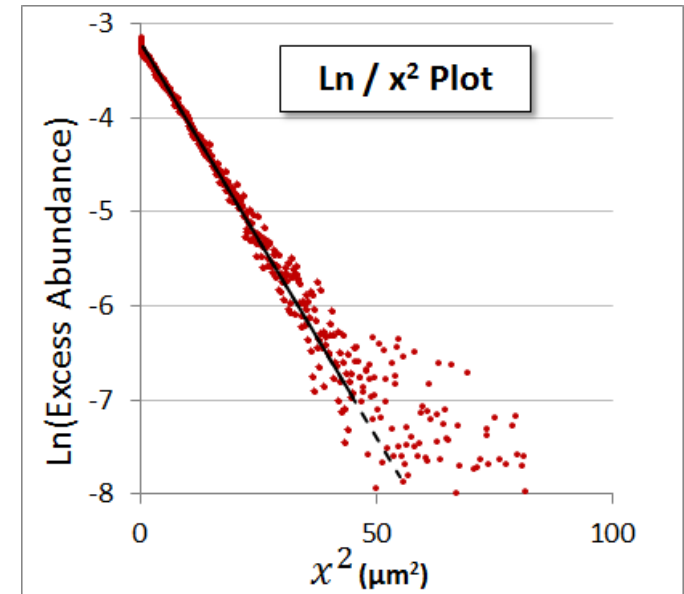
➤ **Optimized SIMS profiles within single grains yield more accurate bulk diffusivities**

Fitting of diffusion depth profiles

Example: SIMS measured excess 25Mg tracer after 350°C ~1hr



Log-linearized plot has fitting problems at low signal levels



Replace concentration with abundance: $C(x, t) - C_1 = \frac{(C_0 - C_1)}{2} \left[\operatorname{erf} \left(\frac{x+h}{2\sqrt{Dt}} \right) - \operatorname{erf} \left(\frac{x-h}{2\sqrt{Dt}} \right) \right]$

Nonlinear fit of D , h and A by minimizing the sum of the square of the residuals:

$$\sum_x \left\{ \underbrace{\left[\frac{I_{\text{tracer}}(x)}{\sum I_{\text{all isotopes}}(x)} - A \right]}_{\text{Experiment}} - \underbrace{\frac{(A_{\text{tracer}} - A_{\text{natural}})}{2} \left[\operatorname{erf} \left(\frac{x+h}{2\sqrt{Dt}} \right) - \operatorname{erf} \left(\frac{x-h}{2\sqrt{Dt}} \right) \right]}_{\text{Theory}} \right\}^2$$

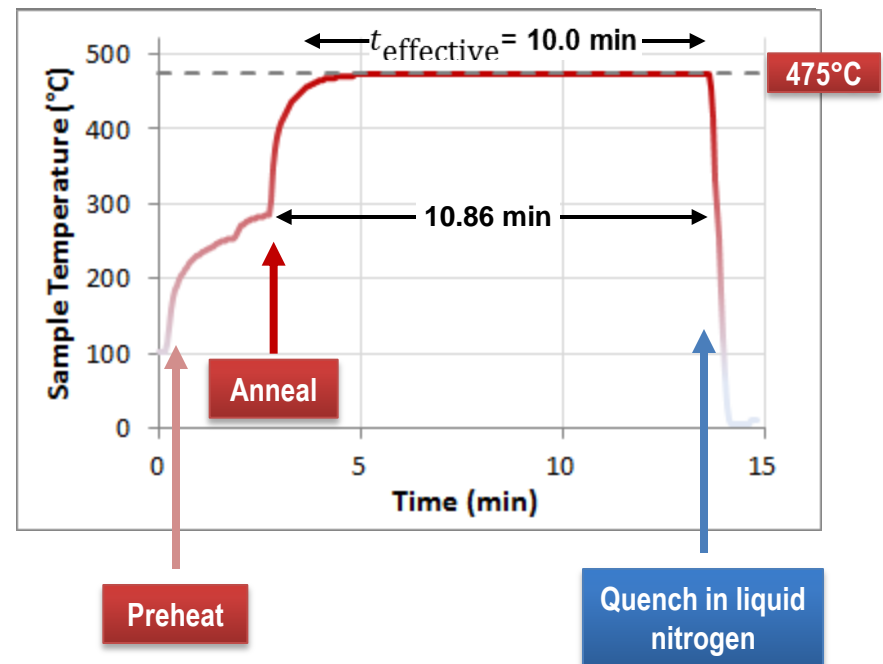
Excess Abundance: Experiment

Theory

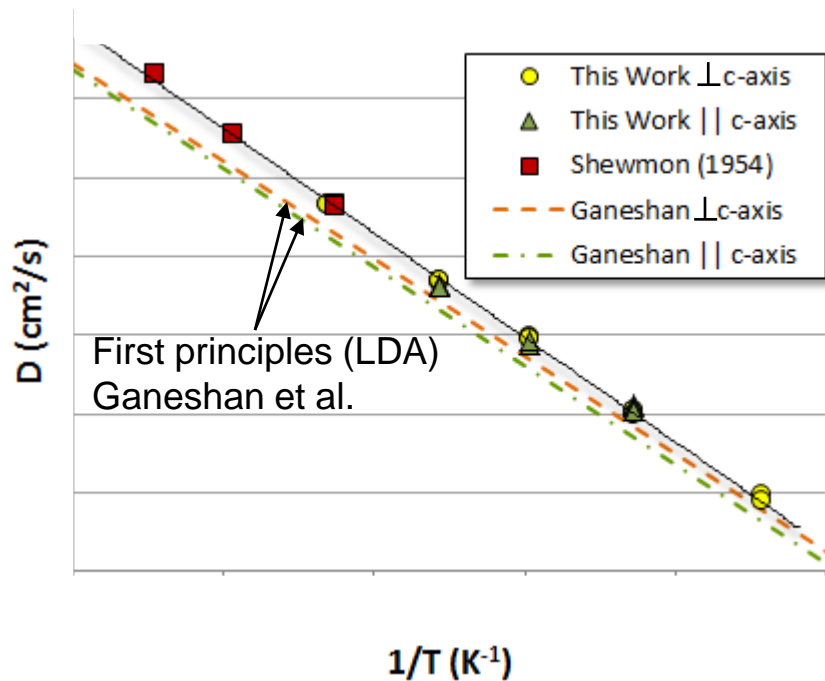
Temperature profile correction

- Effective time at annealing temperature can be calculated using the actual profile and the activation energy (Rothman 1984) using numerical integration
- Capsule design allows rapid change and real-time temperature measurement for precise correction, even for times < 10 minutes
- Example shows 8.6% correction for Mg at 475°C for ~10 minutes

$$t_{\text{effective}} = \int \exp \left[-\frac{Q}{R} \left(\frac{1}{T(t)} - \frac{1}{T_{\text{anneal}}} \right) \right] dt$$



Mg self-diffusion



Spread in fitted diffusivities and comparison of orthogonally cut samples, annealed together at each temperature

T(°C)	s.d. (%)	Max-Min (%)	s.d. (%)	Max-Min (%)	$D_{\perp} - D_{\parallel}$ (%)
	\perp C-axis		\parallel C-axis		
475	0.8	1.1	-	-	-
400	3.2	6.4	1.6	3.1	13.3
350	2.4	4.9	7.7	14.6	14.2
300	5.5	10.3	9.3	20.8	-11.2
250	14.5	20.5	-	-	-

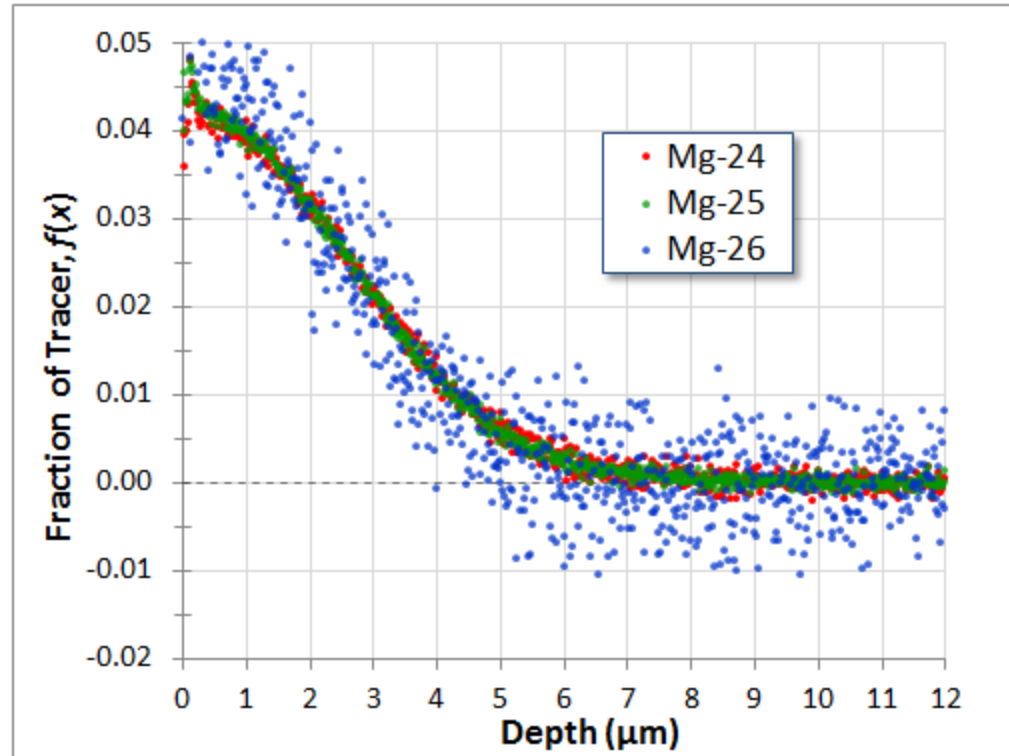
- **Experimental results consistent with polycrystalline radiotracer measurements**
- **Tracer diffusivities in directions parallel to rod axis (\perp C-axis) are typically higher compared to diffusivities normal to rod axis (\parallel C-axis)**

Mg Isotope Comparison

$$f(x) = \frac{A_i(x) - B_i}{T_i - B_i}$$

$A_i(x)$ — measured abundance
 B_i — bulk abundance
 T_i — tracer abundance

- Alternative fitting determines the tracer concentration using each isotope
- The SIMS instrumental bias for each isotope is fully corrected to obtain the abundances with depth, $A_i(x)$ for each isotope i
- Fit of D & h performed
- Small trend observed in D with isotope mass — i.e., lower D with increasing mass

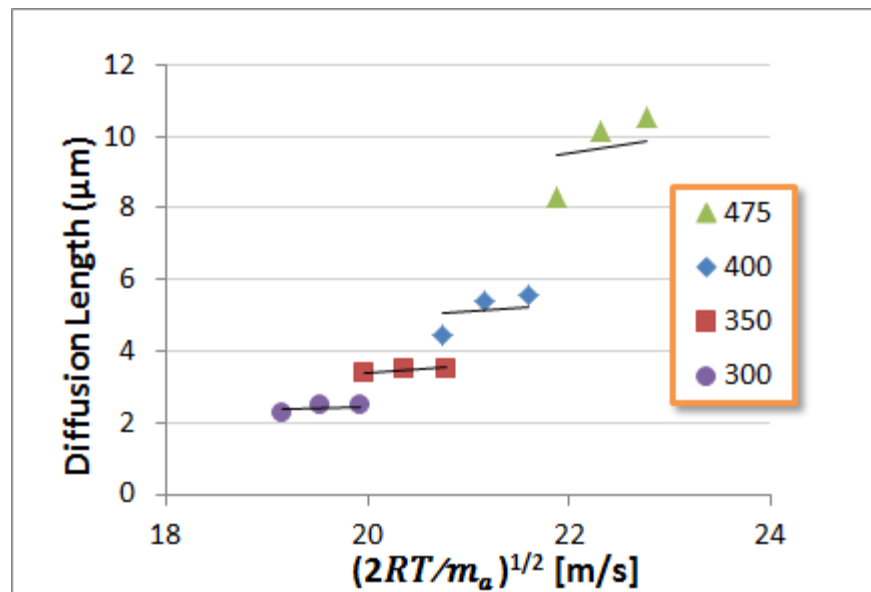


Minimize D , h for each isotope i :

$$\sum_x \left\{ \frac{A_i(x) - B_i}{T_i - B_i} - \frac{1}{2} \left[\operatorname{erf} \left(\frac{x+h}{2\sqrt{Dt}} \right) - \operatorname{erf} \left(\frac{x-h}{2\sqrt{Dt}} \right) \right] \right\}^2$$

Isotope Effect?

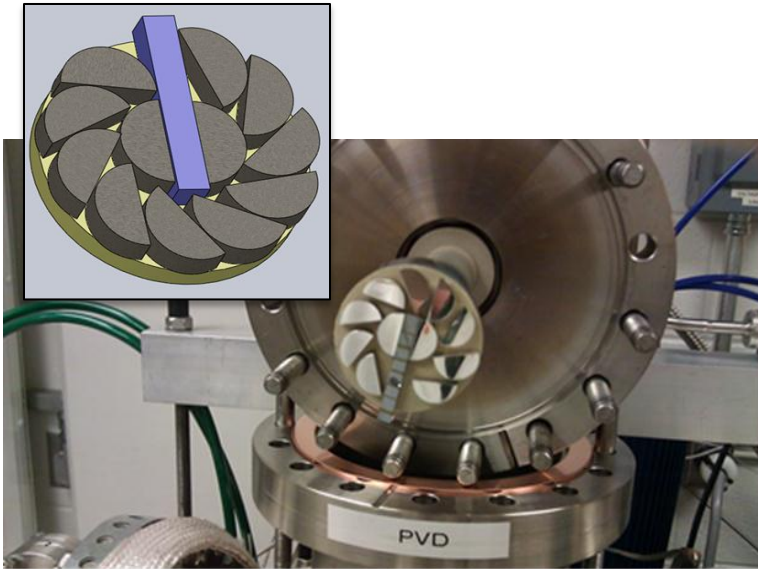
- Trend for slightly lower diffusivity with isotope mass



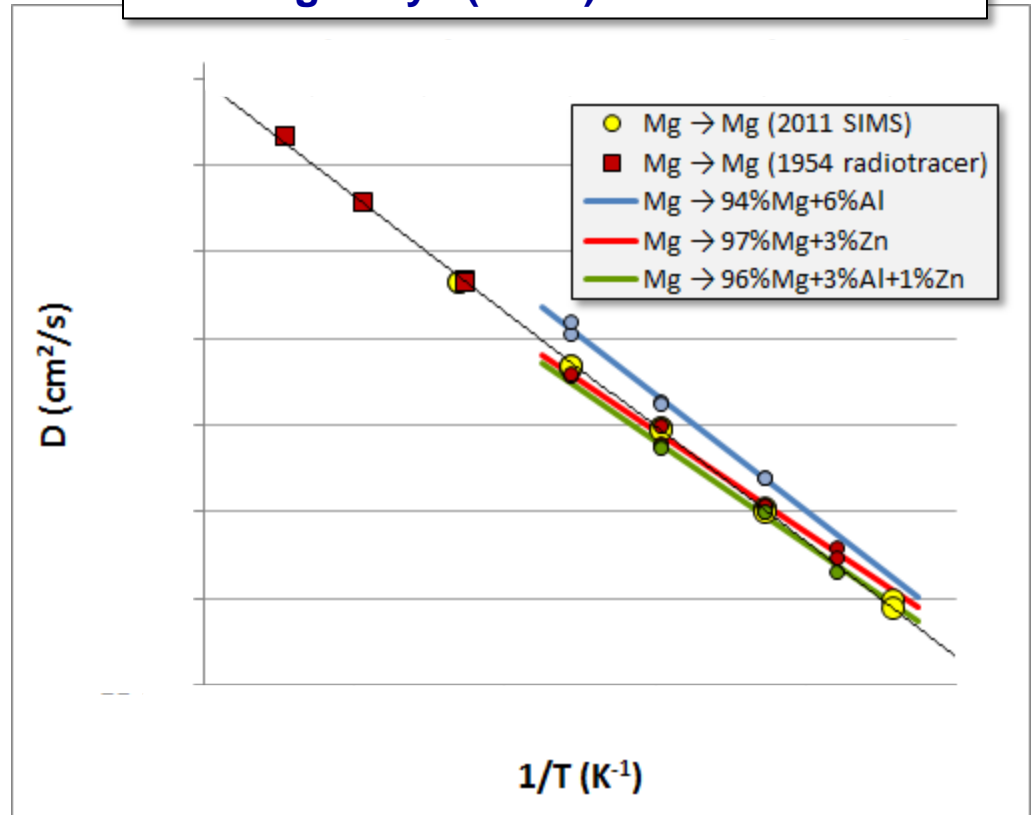
Diffusion length $\sqrt{4Dt}$ with
thermal velocity $\sqrt{2Rt/m}$

Mg tracer diffusion in polycrystalline Mg-Al-Zn alloys

Setup for thin film sputter deposition on Mg alloy samples.



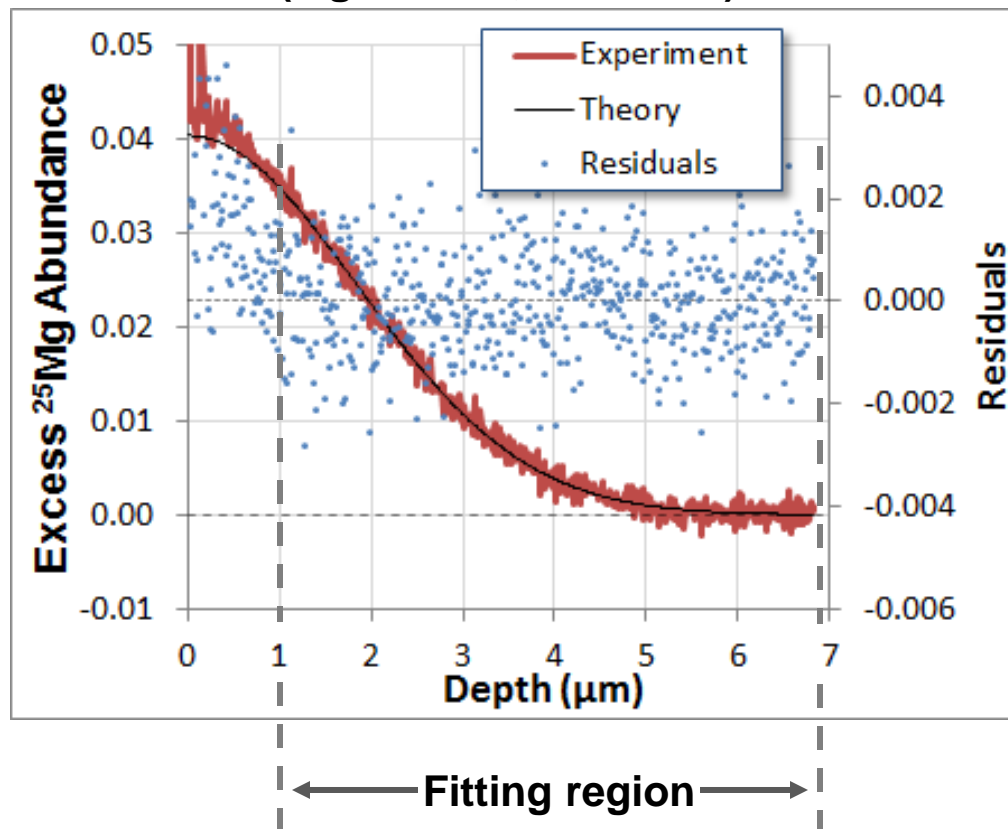
Mg tracer diffusivities as a function of reciprocal temperature for pure Mg and three Mg alloys (Wt %)



Fitting example

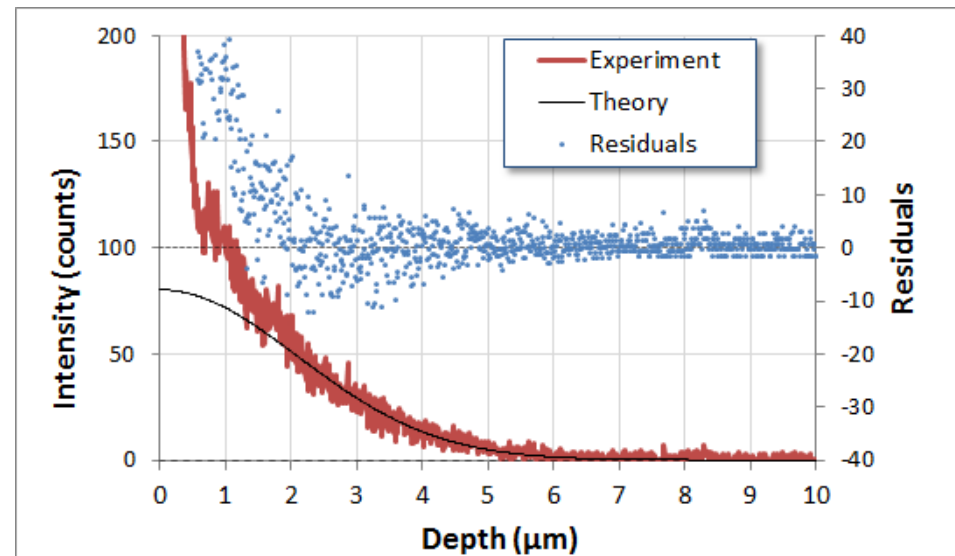
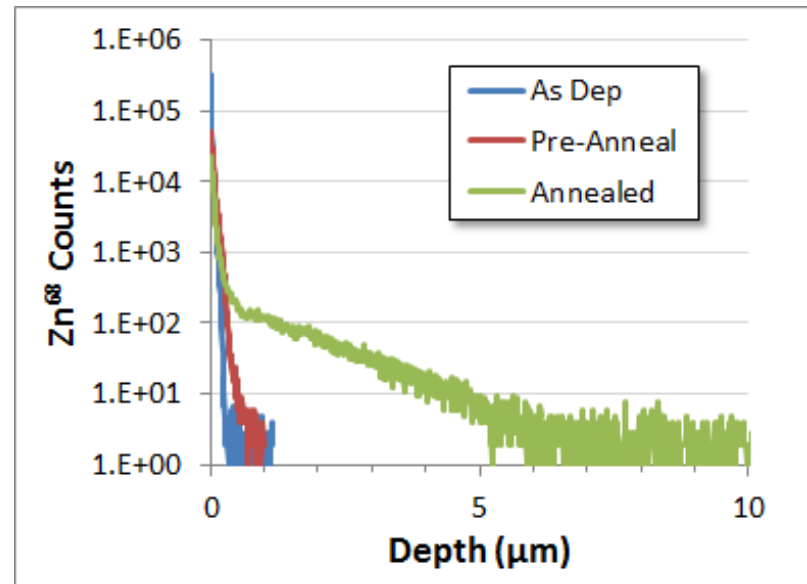
Example: Self diffusion of Mg in MZ3
(Mg: 97wt%, Zn: 3wt%)

- Fitting excludes the Mg-rich zone near the surface

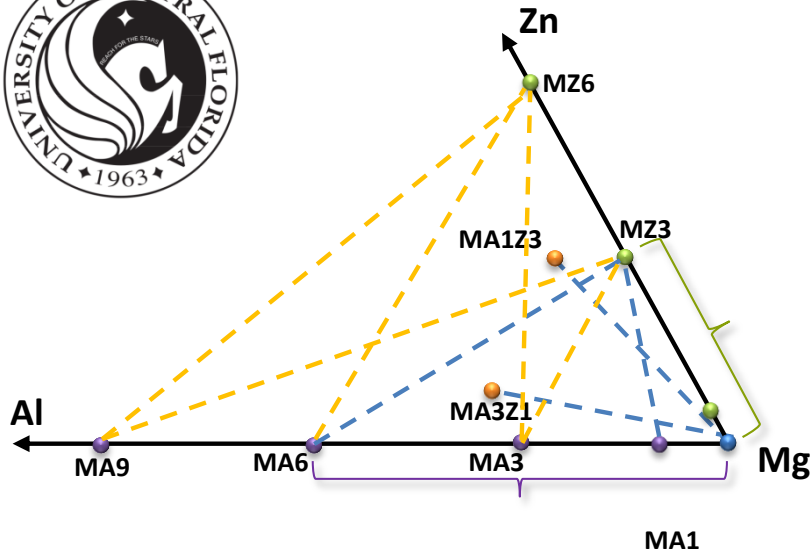


Zn Diffusion

- Pure zinc has a high vapor pressure and would evaporate even at 270°C (~450nm/min)
- Solution: Drive in Zn at 200°C (loss rate of ~5nm/min) to ~100nm, then anneal at diffusion temperature
- Zinc is only weakly soluble in Mg at low temperatures and forms a number of compounds Mg_xZn_y
- Holdup region near surface but good fit in dilute region

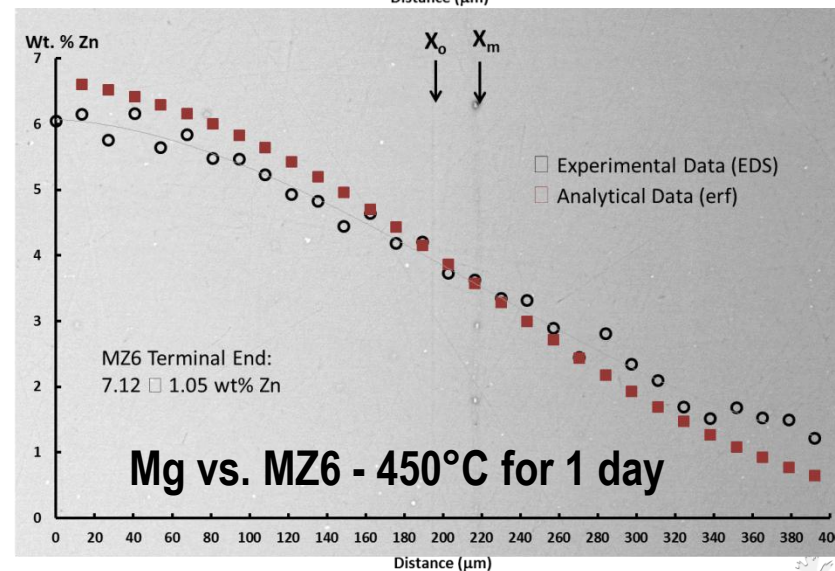
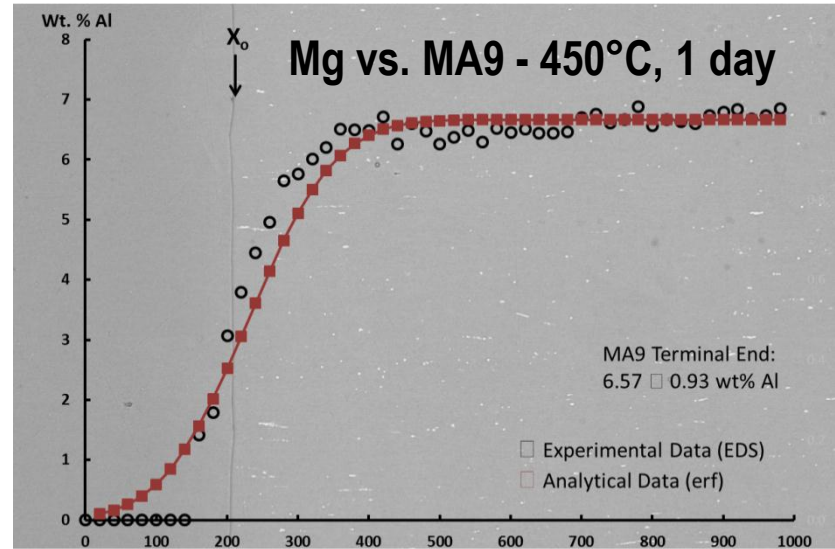


Interdiffusion Studies in Mg-Al-Zn



Selected diffusion couples in hcp Mg-Al-Zn for interdiffusion studies

- Interdiffusion data combined with measured Mg tracer (this work) and thermodynamic data (Φ) is used to compute unknown Al tracer diffusivity using diffusion theory (Darken-Manning relations)



$$D_{\text{inter}} (\text{Mg s.s.}) = [X_{\text{Mg}} D_{\text{Al}}^* + X_{\text{Al}} D_{\text{Mg}}^*] \Phi * S$$

Manning relation in binary Mg-Al

ORNL Diffusion website

Note: The contents of this website are confidential and are restricted to the collaborators listed below and to their in-house associates. The contents are for their personal use and may not be distributed without permission of the PI.

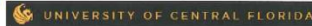
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Isotopic Diffusion Databases for Magnesium Integrated Computational Materials Engineering (Mg-ICME)



- Diffusion
- Interdiffusion
- Theory
- Communications
- Literature

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Industrial Partner: U.S. Automotive Materials Partnership Integrated Computational Materials Engineering (ICME) Team, Magnesium Electron North America

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Resources

- Team Personnel
- UCF Facilities
- SIMS-XPS VaTech

- <http://www.ornl.gov/sci/diffusion> (private)

- Home
- Diffusion
- Interdiffusion
- Theory
- Communications
- Literature

Experimental Progress in Diffusion Studies

- [20120201](#) Mg-25 tracer diffusion into alloys - *new*
- [Zn Tracer](#)
- [20110915-20120120](#) Mg MAZ alloy samples - grain growth and conditioning anneals (*xlsx* catalog)
- [20110823-1109](#) Mg-25 Deposition and Diffusion of Mg-25 into Mg: [Mg Self-Diffusion Summary](#)
- [20110826-0903](#) Temperature Equilibration
- [20110815](#) Mg MAZ alloys - elemental analysis of Mg MAZ alloys
- [20110809](#) Annealing 99.9% Mg, 595°C, 9hr
- [20110801](#) Temperature equilibration of a dummy sample.html
- [20110728](#) Anneal 99.9% Mg, 597°C, 9hr
- [20110719](#) Encapsulation and annealing
- [20110614](#) Annealing attempt with bare Mg pellet

[Alloy Catalog \(xlsx\)](#)
[ASM phase diagrams](#)

Apparatus

- [Annealing encapsulation](#)
- [Annealing Furnace](#)
- [Thermometry](#)
- [Abrasive grit sizes \(xls\)](#)
- [Diamond Sawing](#)
- [Sputter Coating](#)

Mg Abundances			
Isotope	²⁴ Mg	²⁵ Mg	²⁶ Mg
Natural	0.7899	0.1001	0.1100
Tracer1	0.0180	0.9787	0.0033
Tracer2	0.0183	0.9786	0.0031

Al Abundances		
Isotope	²⁶ Al	²⁷ Al
Natural	trace	1.000
Tracer		

Zn Abundances					
Isotope	⁶⁴ Zn	⁶⁶ Zn	⁶⁷ Zn	⁶⁸ Zn	⁷⁰ Zn
Natural	0.4889	0.2781	0.0411	0.1857	0.0062
Tracer	0.0012	0.0011	0.0005	.9971	0.0001
Tracer2 (NA)	0.0099	0.0081	0.0038	0.978	0.0002

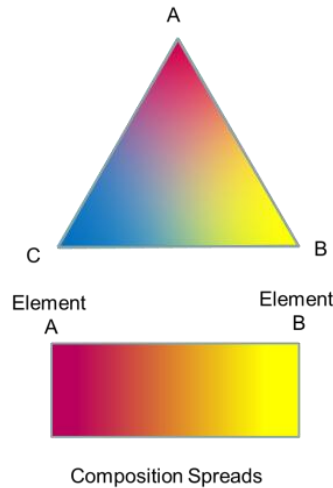
Mn Abundances		
isotope	⁵³ Mn	⁵⁵ Mn
Natural	trace	1.000
Tracer		

- NIST SRM980 [Specs](#)
- [Galv 2003 - Magnesium isotope heterogeneity of the isotopic standard SRM980](#)
- [Coplen 2002 - Isotope Abundance Var of Selected Elements.pdf](#)
- [Rosman 1997 - Isotopic compositions of the elements.pdf](#)

Future Work

- **Continue Mg, Zn tracer diffusion experiments and analysis in Mg-Al-Zn-Mn alloys**
- **Interdiffusion measurements using incremental diffusion couples in Mg-Al-Zn-Mn alloys to extract Al, Mn tracer diffusivities**
- **Mg, Nd, Ce tracer diffusion studies in Mg-Al-Nd, Ce alloys (only preliminary data likely)**
- **Initiate experimental work on continuously selectable alloys (co-sputtered) and grain-boundary diffusion**
- **Ongoing theoretical grain-boundary studies**

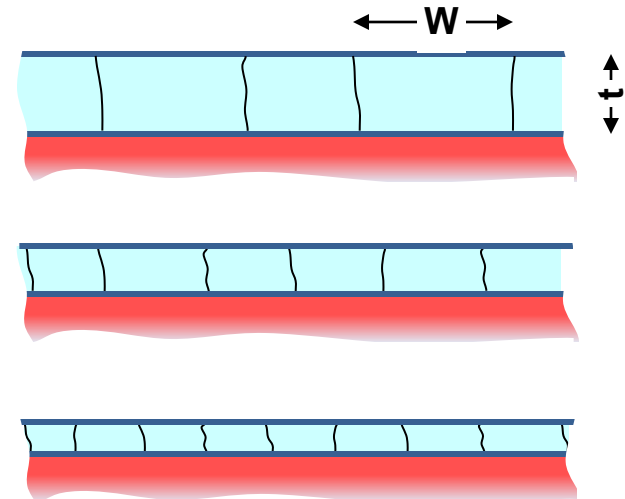
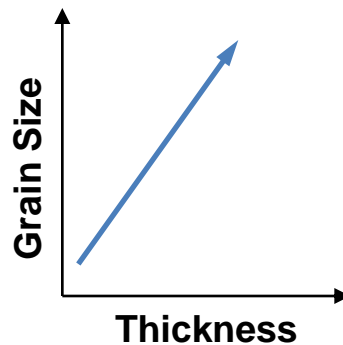
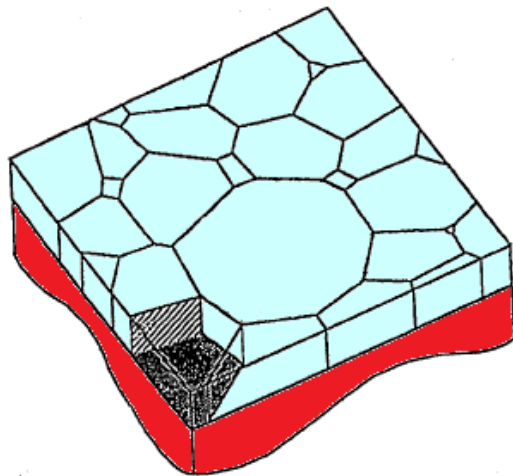
Alloy film magnetron co-sputtering for Mg-alloys & compounds



- Multiple source sputtering system to produce continuously variable alloys and films for grain-boundary studies
 - Uniform composition
 - Wedge variable composition
- Tracer-film deposition *in situ*
- Substrate heating
- UHV base pressure of 10^{-9} Torr
- Load lock sample exchange

Grain boundary diffusion using thin films

- The proportion of diffusion due to bulk and boundary effects can be controlled through grain size
- Grain size is generally pinned by top and substrate boundaries to be $\sim 2X$ the thickness of annealed thin films
- Co-deposition of Mg, Al and Zn produces variety of alloy films for diffusion studies



Summary

- **Relevance**

- A tracer diffusion database in Mg alloys is of fundamental importance to the **ICME** and other integrated materials design efforts (e.g., **Materials Genome Initiative**) in establishing design and modeling tools, optimizing manufacturing processes, and predicting performance requirements.

- **Key accomplishments/progress**

- **Established SIMS based tracer diffusion technique**
- Obtained Mg self-diffusivities in pure polycrystalline Mg samples using our SIMS-based thin-film stable-isotope technique, validating and extending historic radiotracer measurements to lower temperatures.
- Obtained Mg & Zn tracer diffusivities in a number of alloys in the Mg-Al-Zn system.
- Developed a superior annealing technique for Mg based on the Shewmon-Rhines approach.
- Diffusion website facilitates communication between local and international collaborators, and served as a repository for data, experiments, analysis, theory and relevant literature.